Inventor: Cobbley et al. Docket No.: 2269-3437.9US

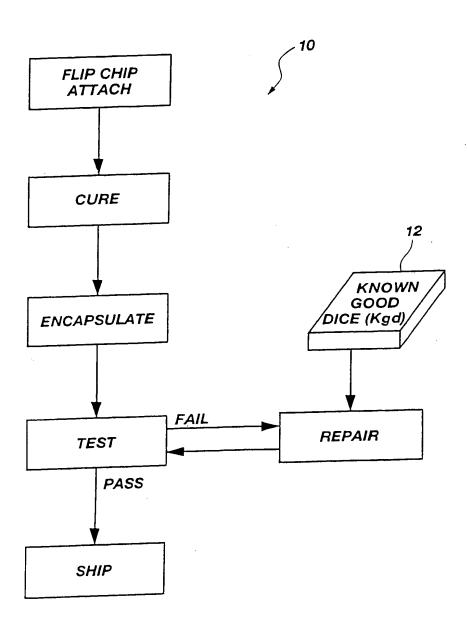


Fig. 1 (PRIOR ART)

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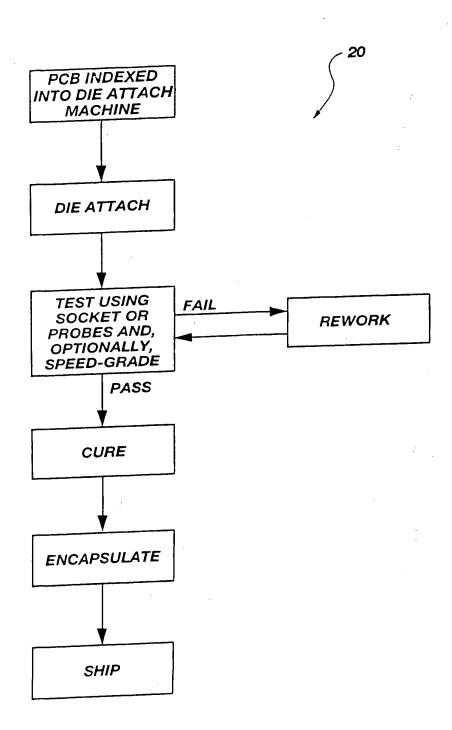


Fig. 2

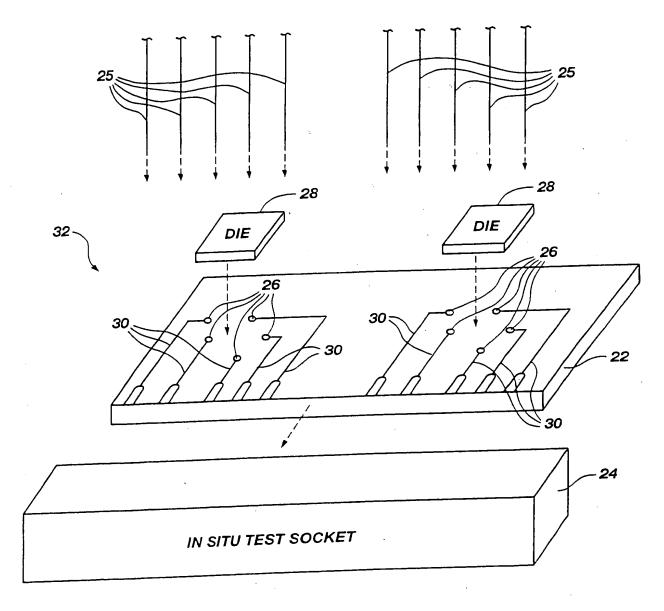
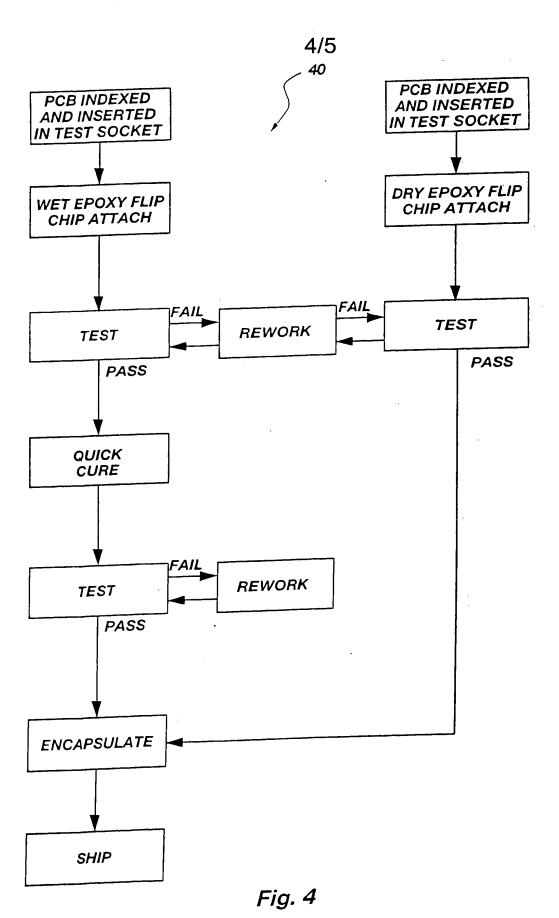


Fig. 3

Inventor; Cobbley et al. Docket No.: 2269-3437.9US



TITLE: METHOD FOR IN-LINE TESTING OF FLIP-CHIP SEMICONDUCTOR ASSEMBLIES Inventor: Cobbley et al. Docket No.: 2269-3437.9US

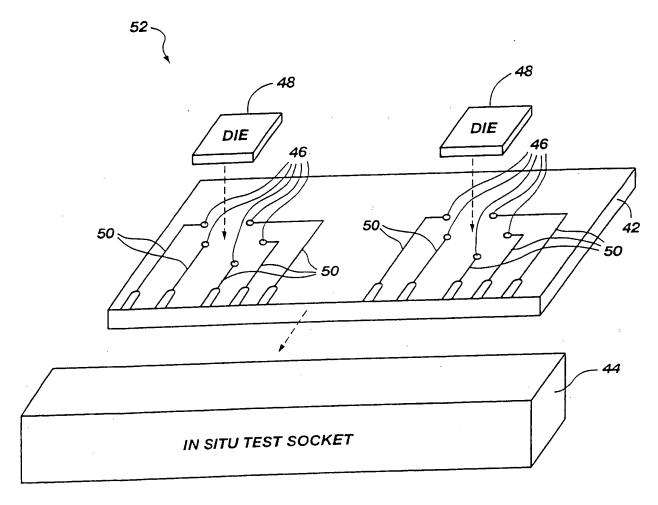


Fig. 5